

# Stochastic inverse problems with impulsive noise

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Chemnitz Symposium on Inverse Problems

Chemnitz, September 18, 2014

## Impulsive noise

- appears in digital image acquisition, processing (hardware defects, cosmic rays, ...)
- characterization: noise is “sparse”, acts pointwise
- e.g., random-valued impulsive noise

$$\eta(x_i) = \begin{cases} \xi_i & \text{with probability } \lambda \\ 0 & \text{with probability } 1 - \lambda \end{cases}$$

$\xi_i \in \mathcal{N}(0, \sigma^2)$  i.i.d. Gaussian,  $\lambda > 0$

- meaningless in function space!

## Goal:

- rigorous definition of **continuous** impulsive noise model
- analysis of **stochastic inverse problems** with impulsive noise
- **conforming** discretization reproducing discrete noise

## Approach:

- model impulsive noise as point process  $\rightsquigarrow$  **random measure**
- relate noise level to noise parameters
- discretization by averaging  $\rightsquigarrow$  linear combination of Diracs

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## Poisson point process:

- random countable set  $\Pi \subset \Omega \subset \mathbb{R}^n$
- intensity measure  $\mu$  (here:  $\mu(A) = \lambda|A|$  for  $\lambda > 0$ )
- counting measure  $N : A \mapsto \#(\Pi \cap A)$

satisfying

- 1  $A_i \subset \Omega$  disjoint, measurable  $\Rightarrow N(A_i)$  independent
- 2  $A \subset \Omega$  measurable  $\Rightarrow N(A)$  Poisson distributed with mean  $\mu(A)$ ,

$$\mathbb{P}[N(A) = k] = e^{-\mu(A)} \frac{\mu(A)^k}{k!}$$

Marked Poisson point process:

$$\Pi^* = \{(x, \xi_x) : x \in \Pi, \xi_x \in \mathcal{N}(0, \sigma^2)\}$$

- $x \in \Pi$  denotes **location** of corrupted point
- $\xi_x$  i.i.d denotes **magnitude** of corruption
- Poisson point process on  $\Omega \times \mathbb{R}$
- statistical model for physical cause (e.g., cosmic rays)
- defines **random measure**

$$\eta = \sum_{(x, \xi_x) \in \Pi^*} \xi_x \delta_x$$

- $\Omega$  bounded  $\rightsquigarrow$   $\Pi$  finite,  $\eta \in \mathcal{M}(\Omega) = \mathcal{C}(\overline{\Omega})^*$  almost surely

- Expectation: for  $A \subset \Omega$ ,

$$\mathbb{E}[\eta(A)] = \sum_{k=1}^{\infty} \mathbb{P}[N(A) = k] \sum_{x \in \Pi \cap A} \int_{\mathbb{R}} \xi_x \, dv = 0$$

- Variance: for  $A \subset \Omega$ ,

$$\begin{aligned} \text{Var}[\eta(A)] &= \sum_{k=1}^{\infty} \mathbb{P}[N(A) = k] \sum_{x \in \Pi \cap A} \int_{\mathbb{R}} \xi_x^2 \, dv \\ &= \sum_{k=1}^{\infty} e^{-\lambda|A|} \frac{(\lambda|A|)^k}{k!} k \sigma^2 \\ &= \lambda \sigma^2 |A| \end{aligned}$$

$$\varepsilon(\eta) := \|\eta\|_{\mathcal{M}(\Omega)} = \sup_{\|\varphi\|_{C(\bar{\Omega})} \leq 1} \sum_{(x, \xi_x) \in \Pi^*} \xi_x \langle \delta_x, \varphi \rangle = \sum_{(x, \xi_x) \in \Pi^*} |\xi_x|$$

Campbell's theorem,  $|\xi_x|$  i.i.d. and half-normal  $\rightsquigarrow$

$$\mathbb{E}[\varepsilon(\eta)] = \int_{\Omega} \int_{\mathbb{R}} |\xi_x| d\mu dv = \lambda |\Omega| \int_{\mathbb{R}} |\xi| dv = \lambda \sigma |\Omega| \sqrt{\frac{2}{\pi}}$$

$$\text{Var}[\varepsilon(\eta)] = \int_{\Omega} \int_{\mathbb{R}} |\xi_x|^2 d\mu dv = \lambda |\Omega| \int_{\mathbb{R}} |\xi|^2 dv = \lambda \sigma^2 |\Omega| \left(1 - \frac{2}{\pi}\right)$$



Consider  $\{\eta_n\}_{n \in \mathbb{N}} \subset \mathcal{M}(\Omega)$  for  $\lambda_n, \sigma_n > 0$

1 If  $\lambda_n \sigma_n \rightarrow 0$ :

$$\mathbb{E}[\varepsilon(\eta_n)] = \mathcal{O}(\lambda_n \sigma_n) \rightarrow 0$$

2 If also  $\lambda_n \sigma_n^2 = \mathcal{O}(n^{-r})$  for  $r > 1$  (e.g., subsequence):

$$\varepsilon(\eta_n) \rightarrow 0 \quad \text{almost surely}$$

Proof:

- Chebyshev concentration inequality + Borel–Cantelli
- not constructive  $\rightsquigarrow$  no uniform a priori bounds, no rates

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$$\min_{u \in X} \|F(u) - y^\varepsilon(\omega)\|_{\mathcal{M}(\Omega)} + \alpha \mathcal{R}(u),$$

- $X$  Banach space,  $\mathcal{R}$  convex, l.s.c., weakly sequentially precompact sublevel sets
- e.g.,  $\mathcal{R}(u) = \frac{1}{2} \|u\|_X^2$
- $F : X \rightarrow \mathcal{M}(\Omega)$  bounded, weak-to-strong continuous (compact embedding  $F : X \rightarrow Y \hookrightarrow \mathcal{M}(\Omega)$ )
- $y^\varepsilon = F(u^\dagger) + \eta$  random noisy data,  $y^\varepsilon(\omega)$  realization

$$\min_{u \in X} \|F(u) - y^\varepsilon(\omega)\|_{\mathcal{M}(\Omega)} + \alpha \mathcal{R}(u),$$

Standard arguments: for every  $\alpha > 0$  and realization  $y^\varepsilon(\omega) \in \mathcal{M}(\Omega)$ :

- existence of minimizer  $u_\alpha^\varepsilon(\omega)$
- $y_n \rightarrow y^\varepsilon(\omega)$  implies  $u_\alpha^n \rightarrow u_\alpha^\varepsilon(\omega)$
- if  $\mathcal{R}$  strictly convex,  $u_\alpha^\varepsilon(\omega)$  unique

$\rightsquigarrow$  defines random field  $u_\alpha^\varepsilon$

Consider

- sequence  $\{\eta_n\}$  for  $\lambda_n, \sigma_n$  with

$$\lambda_n \sigma_n \rightarrow 0$$

- noisy data  $y_n := F(u^\dagger) + \eta_n$ , minimizer  $u_n := u_{a_n}^{\varepsilon_n}$

If  $a_n \rightarrow 0$  and  $\frac{\lambda_n \sigma_n}{a_n} \rightarrow 0$

then subsequence  $\mathbb{E}[u_n] \rightarrow u^\dagger$

- proof: standard deterministic arguments + convergence of  $\varepsilon_n$   
[Bissantz/Hohage/Munk '04]
- full sequence if  $u^\dagger$  unique, strong convergence if  $\mathcal{R}$  Kadec–Klee

Consider

- sequence  $\{\eta_n\}$  for  $\lambda_n, \sigma_n$  with

$$\{\lambda_n\}, \{\sigma_n\} \text{ bounded, } \lambda_n \sigma_n = \mathcal{O}(n^r) \text{ for } r > 1$$

- noisy data  $y_n := F(u^\dagger) + \eta_n$ , minimizer  $u_n := u_{a_n}^{\varepsilon_n}$

If  $a_n \rightarrow 0$  and  $\frac{\lambda_n \sigma_n^2}{a_n} \rightarrow 0$

then subsequence  $u_n \rightharpoonup u^\dagger$  almost surely

- proof: standard deterministic arguments + convergence of  $\varepsilon_n$   
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Under usual assumptions:

- 1 A priori choice:  $\alpha \sim (\lambda\sigma)^\tau$  for  $\tau \in (0, 1)$

$$\mathbb{E} \left[ \|u_\alpha^\varepsilon - u^\dagger\|_X \right] \leq c(\lambda\sigma)^{\frac{1-\tau}{2}}$$

- 2 Morozov:  $\tau_1\lambda\sigma \leq \|F(u_\alpha^\varepsilon) - y^\varepsilon\|_{\mathcal{M}(\Omega)} \leq \tau_2\lambda\sigma$

$$\mathbb{E} \left[ \|u_\alpha^\varepsilon - u^\dagger\|_X \right] \leq c(\lambda\sigma)^{\frac{1}{2}}$$

- no almost sure rates, since no such rates for  $\varepsilon_n$
- for  $\sigma$  bounded: rates independent of  $\sigma$   
 $\rightsquigarrow \lambda$  essentially characterizes noise level; robustness

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**Approach:** start with discretization of  $C(\overline{\Omega})$  [Casas/C./Kunisch '12]

- $\{x_j\}_{j=1}^{N_h} \subset \Omega$  nodes (sampling points, pixel midpoints, vertices)
- $\{e_j\}_{j=1}^{N_h}$  **nodal basis** of continuous functions (FEM basis, point spread functions)
- $h := \max_{1 \leq j \leq N} h_j, \quad h_j := |\text{supp } e_j|$

$$C_h := \left\{ v_h \in C(\overline{\Omega}) : v_h = \sum_{j=1}^{N_h} v_j e_j, \text{ where } \{v_j\}_{j=1}^{N_h} \subset \mathbb{R} \right\}$$

$$M_h := \left\{ \mu_h \in \mathcal{M}(\Omega) : \mu_h = \sum_{j=1}^{N_h} \mu_j \delta_{x_j}, \text{ where } \{\mu_j\}_{j=1}^{N_h} \subset \mathbb{R} \right\}$$

with norm

$$\|\mu_h\|_{\mathcal{M}(\Omega)} = \sup_{\|v\|_{C(\bar{\Omega})}=1} \sum_{j=1}^{N_h} \mu_j \langle \delta_{x_j}, v \rangle = \sum_{j=1}^{N_h} |\mu_j| =: |\vec{\mu}_h|_1$$

$\rightsquigarrow M_h$  **topological dual** of  $C_h$  with respect to duality pairing

$$\langle \mu_h, v_h \rangle = \sum_{j=1}^{N_h} \mu_j v_j = \vec{\mu}_h^T \vec{v}_h$$

$$\begin{aligned}\Pi_h : C(\bar{\Omega}) &\rightarrow C_h, & \Pi_h v &= \sum_{j=1}^{N_h} \langle v, \delta_{x_j} \rangle e_j \\ \Lambda_h : \mathcal{M}(\Omega) &\rightarrow M_h, & \Lambda_h \mu &= \sum_{j=1}^{N_h} \langle \mu, e_j \rangle \delta_{x_j}\end{aligned}$$

↪ For all  $\mu \in \mathcal{M}(\Omega)$ ,  $v \in C(\bar{\Omega})$ ,  $v_h \in C_h$ :

- 1  $\langle \mu, v_h \rangle = \langle \Lambda_h \mu, v_h \rangle$  and  $\langle \mu, \Pi_h v \rangle = \langle \Lambda_h \mu, v \rangle$
- 2  $\|\Lambda_h \mu\|_{\mathcal{M}(\Omega)} \leq \|\mu\|_{\mathcal{M}(\Omega)}$
- 3  $\Lambda_h u \xrightarrow{*} u$  in  $\mathcal{M}(\Omega)$  and  $\|\Lambda_h u\|_{\mathcal{M}(\Omega)} \rightarrow \|u\|_{\mathcal{M}(\Omega)}$

Define **discrete noise**  $\eta_h$  via

$$\begin{aligned}\eta_h(\omega) &:= \Lambda_h[\eta(\omega)] = \sum_{j=1}^{N_h} \langle \eta, e_j \rangle \delta_{x_j} \\ &= \sum_{j=1}^{N_h} \left( \sum_{x \in \Pi \cap \text{supp } e_j} e_j(x) \xi_x(\omega) \right) \delta_{x_j} \\ &=: \sum_{j=1}^{N_h} \eta_j(\omega) \delta_{x_j}\end{aligned}$$

- nodes  $x_j$  deterministic  $\rightsquigarrow$  identify  $\eta_h$  with  $(\eta_1, \dots, \eta_j) \in \mathbb{R}^{N_h}$
- **averaging**  $\rightsquigarrow$  model of physical image acquisition by sensors

Case differentiation:

1  $\eta_j = 0$ : iff  $\text{supp } e_j \cap \Pi = \emptyset \rightsquigarrow$

$$\mathbb{P}(\mu_j = 0) = \mathbb{P}(N(\text{supp}(e_j)) = 0) = e^{-\lambda h}$$

2  $\eta_j \neq 0$ : then

$$\eta_j(\omega) = \sum_{x \in \Pi \cap \text{supp}(e_j)} e_j(x) \xi_x(\omega)$$

a.s. finite linear combination of Gaussian  $\rightsquigarrow$  Gaussian,  $\mathbb{E}[\eta_h] = 0$ ,

$$\text{Var}[\mu_j] = \lambda \int_{\Omega} e_j(x)^2 dx \int_{\mathbb{R}} \xi^2 dv =: \lambda s_j \sigma^2$$

with  $s_j \leq h_j \leq h$  (Campbell's theorem)

Discrete noise model in uniform case  $s_j \equiv s \approx h$ :

$$\eta_h(x_j) = \eta_j = \begin{cases} 0 & \text{with probability } 1 - \lambda_h \\ \xi_j \in \mathcal{N}(0, \sigma_h^2) & \text{with probability } \lambda_h \end{cases}$$

$$\lambda_h := 1 - e^{-\lambda h}, \quad \sigma_h \approx \lambda \sigma^2 h$$

- effective noise parameters  $\lambda_h, \sigma_h$  discretization dependent
- $\sigma_h$  depends on  $\sigma$  and  $\lambda$
- note: taking  $h \rightarrow 0$  here meaningless since  $\eta_h \rightarrow^* \eta$

$$\varepsilon_h := \|\eta_h\|_{\mathcal{M}(\Omega)} = \sum_{j=1}^{N_h} |\eta_j|$$

- $|\eta_j|$  half-normal random variable (not independent!)
- $\rightsquigarrow$  moments from Campbell's theorem
- $\Lambda_h$  interpolation  $\rightsquigarrow \varepsilon_h \leq \varepsilon$  almost surely,

$$\mathbb{E}[\varepsilon_h] \leq \mathbb{E}[\varepsilon]$$

$$\text{Var}[\varepsilon_h] \leq \text{Var}[\varepsilon]$$

$$\min_{u \in X} \|F_h(u) - y_h^\varepsilon\|_{\mathcal{M}(\Omega)} + \alpha \mathcal{R}(u)$$

- $F_h := (\Lambda_h \circ F) : X \rightarrow M_h$
- $y_h^\varepsilon := \Lambda_h y^\varepsilon = F_h(u^\dagger) + \eta_h \in M_h$
- semi-discretization (discretization of  $X$  independent)
- conforming discretization  $\rightsquigarrow$  **well-posed**, solution  $u_h := u_\alpha^{\varepsilon_h}$
- $\varepsilon_h$  uniformly bounded  $\rightsquigarrow$  convergence, rates (**uniform** in  $h$ )



Consider

- noise parameters  $\lambda, \sigma$  fixed
- discretization parameter  $h \rightarrow 0$

Then:  $\{u_h^\varepsilon\}_{h>0}$  contains subsequences with

- 1  $\mathbb{E}[u_\alpha^{\varepsilon h}] \rightarrow \mathbb{E}[u_\alpha^\varepsilon]$
  - 2  $u_\alpha^{\varepsilon h} \rightarrow u_\alpha^\varepsilon$  almost surely
- whole sequence if  $u_\alpha$  unique, strong convergence if  $\mathcal{R}$  Kadec–Klee
  - proof: boundedness of  $\Lambda_h$ , standard arguments

## Continuous impulsive noise:

- Poisson point process is appropriate model
- conforming discretization reproduces standard discrete noise
- convergence of stochastic inverse problem

## Outlook:

- numerical realization (based on [C./Jin '12])
- adaptive discretization & regularization
- heuristic parameter choice
- fitting with probability metrics